

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Jeffrey T. Fanton, et al.

Application No.: 10/053,373

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For: X-RAY REFLECTANCE

MEASUREMENT SYSTEM WITH ADJUSTABLE RESOLUTION

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Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 **CERTIFICATE OF MAILING**

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